Searcl	h Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/646,638	JOHN G. KURTH	
Examiner Harry S. Hong	Art Unit	
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2614

SEARCHED					
Class	Subclass	Date	Examiner		
379	188 189 190	8/2/2007	Н		
	196				
	196 197 198 207.01 210.02 211.02				
	210.02				
	212.01				
SEARCHED ABove W/	ALL OF KEYWORDS				

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SEARCH NOT (INCLUDING SEARCH)
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